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Pixel designs and High Dynamic Range pixels


Software High Dynamic Range methods, tone-mapping algorithms, and perception


**Measurement and characterization methods**


**General HDR**


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Aphesa is a young, privately owned company founded in 2008, specializing in image sensor consulting, high dynamic range imaging, as well as image sensor and camera characterization, design, and benchmarking. Aphesa is one of the technical contributors to the EMVA1288 (European Machine Vision Association) standard for characterization of machine vision sensors and cameras, and characterization data reporting.